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| DATE: | April 21, 2005 | TOTAL # OF PAGES: (INCLUDING THIS COVER SHEET) | 4 pgs. |
| TO: | Examiner Hien Phan | FAX #: | 703-571-9306 |
| FIRM NAME: | United States Patent Office | PHONE #: | 571-272-1606 |
| FROM: | Frances L. Essien | FAX #: | (612) 340-8856 |
| PHONE #: | (612) 340-7849 | EMAIL: | essien.frances@dorsey.com |

COMMENTS:

Re: U.S. Patent Application
 Title: Anti-Reflection Coating for a Temperature Sensitive Substrate
 Appln. No.: 08/914,868
 Date Filed: August 19, 1997
 Dkt. No.: 6374

Dear Examiner Phan:

In a follow up to our telephone conversation, attached please find a copy of the response that we filed responding to Office Communication dated September 18, 2003.

Thank you for your assistance.

Frances Essien

Paralegal

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REFERENCE # 712434881-127

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Docket: 6374

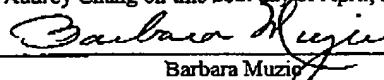
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| | | |
|-----------------------|---|----------------------|
| First Named Inventor: | Erik J. Bjornard et al. | |
| Appn. No.: | 08/914,868 | |
| Filing Date: | August 19, 1997 | Examiner: A. Chang |
| Title: | Anti-reflection Coating for a Temperature Sensitive Substrate | Group Art Unit: 2872 |

**FOLLOW-UP REQUEST FOR ENTRY OF AMENDMENT
AND ALLOWANCE OF REISSUE APPLICATION**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

I hereby certify that this document is being sent via facsimile to Examiner Audrey Chang on this 20th day of April, 2005.



Barbara Muzio

Sir:

It is respectfully requested that Applicant's earlier Response to the Office Communication dated July 1, 2003 be entered and that the reissue application be allowed.

In the Office Communication dated July 1, 2003, certain claims were objected to for the reason that the amendment format did not comply with 37 CFR 1.173, among other objections.

In a Response mailed July 30, 2003, Applicant responded to each of the Examiner's objections, including reflecting changes to the specification and claims in compliance with 37 CFR 1.173.

In an Office Communication dated September 18, 2003, the Examiner merely indicated that:

"The amendment filed by the Applicant on August 4, 2003 is NOT compliant with the requirements. The amendment, therefore, is not entered."

Attached to this Office Communication was a copy of a revised Amendment Practice indicating that 37 CFR § 1.121 has changed.

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As far as Applicant is concerned, the earlier filed Response to the Office Communication of July 1, 2003 was in full compliance with 37 CFR § 1.173. Rule 1.121 does NOT apply to reissues.

On September 30, 2003, in response to a call requesting clarification, Examiner Cassandra Spyrou advised that she was no longer the Supervisory Examiner for the above application and gave us the name of Examiner Drew Dunn as being the current Supervisory Examiner. That afternoon in a telephone conference with Examiner Dunn for the purpose of determining more specifically why the amendment did not comply with the requirements of Rule 1.173, Examiner Dunn indicated that he would look at the file history and would call back by the end of that week or the beginning of the next week or the beginning of the next week.

Having heard nothing from Examiner Dunn, a telephone call was placed to Examiner Dunn on June 1, 2004 and a message was left for him to return the call regarding the above application. No return call was made.

In a follow-up call on June 18, 2004 to Examiner Dunn, a further telephone message was left to return the call. Again, no call was returned.

Again, having heard nothing from Examiner Dunn, a further telephone call was made to Examiner Dunn on March 3, 2005 and a message was left to return the call.

On March 9, 2005, a telephone conference was held with Examiner Dunn who suggested we talk to Clayton Labelle. Mr. Labelle indicated that he was going to contact Hien Phan who will, in turn, contact Audrey Chang (the Primary Examiner) to discuss the matter and have the Examiner contact us. Having heard nothing, a further telephone call was made to Examiner Phan on March 28, 2005 with a message to return the call.

A follow-up telephone call to Examiner Phan was made on April 20, 2005. Examiner Phan instructed us to file the present reply.

Applicant believes that all amendments to the specification and claims are in compliance with Rule 1.173 and that the application is in condition for allowance.

Accordingly, it is requested that the earlier filed Response to the Office Communication of July 1, 2003 be entered and that the application be allowed, or that the Examiner be more specific with respect to the manner in which he/she believes the amendments fail to comply with Rule 1.173.

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Prompt reconsideration is respectfully requested.

Respectfully submitted,

DORSEY & WHITNEY LLP

Date: April 20, 2005
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